

Surface Fest 2018

HORIBA scientific is pleased to organize the 1st Surface Fest on the 13 & 14 June at Palais des congrès Bordeaux-France during the conference SVTM 2018.

This international conference aims to gather researchers and end-users interested in Glow Discharge Spectrometry and Spectroscopic Ellipsometry for surface characterization.

The first day will highlight materials challenges for emerging applications.

The two sessions of the second day will permit to share experiences for both GDOES and Ellipsometry.

WHEN

June 13th and 14th, 2018

The Surface Fest will last two days, starting on Wednesday June 13 morning and continuing until the Thursday 14 end of day. This will give ample time for presentations and discussions. It will be held in parallel to the SFP Plasma 2018, 15th Congress of the Plasmas Division of French Physical Society (SFP).

WHAT

- The Surface Fest is dedicated to GDOES and Ellipsometers users but also open to people interested by applications and researches in the field. Synergies with other techniques will be highlighted.
- **Call for abstracts** is still open for oral presentations and posters, please go to our website and submit an abstract.
- Posters will be on display during the whole duration in exhibition hall - allowing more people to come and see your work.

WHERE

Surface Fest 2018 will be held at Palais des Congrès de Bordeaux, France.

COST

Standard: €150

Includes refreshments, lunch and diner on the 13th, lunch on 14th. Does not include hotel accommodation.

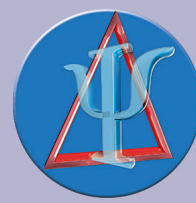
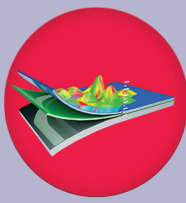
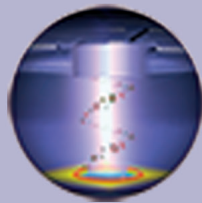
SCHEDULE

May 2018 – Registration Closes

June 2018 – Surface Fest

Already confirmed talks and speakers (1)

- Dr Anouk Galtayries and Dr Frederic Wiame, IRCP/PCS, Chimie Paris Tech, PSL Université Paris, «**Surfaces: matter for innovation, basics and related techniques**»
- Professor Ray-Hua Horng, Institute of Electronics, National Chiao Tung University President, Taiwan Vacuum Society, and Professor Dong Sing Wu, National Chung Hsing University, Taiwan, «**Development and progress of microLED Display Technology**»
- Professor Yvan Bonassieux, Ecole Polytechnique, France, «**Organic material and hybrid perovskite a possible futur for low cost flexible electronic** »
- Dr. Olaf Zywitzki, Fraunhofer Institute for Organic Electronics, Electron Beam and Plasma Technology FEP, Materials Analysis Head of Department, Dresden, Germany, «**Characterization of ITO films on thin glass substrates**»
- Dr Alessandra Sergent & Dr Carlos Gomes-Vieira, Renault, France
- Dr Sebastien Cremel, Evelyne Gagatck, V. Philippe, MJ Cornu, F. Broquedis, L. Gigli, Surface and coatings, ArcelorMittal, Global Research and Development Maizières Automotive Products, Maizières, France, « **Surface analytical techniques in support to industrialization of coated steel products**»
- Professor Herve Martinez, Professeur des universités, Directeur Adjoint IPREM CNRS UMR 5254 Helioparc, Pau, France, «**Electrochemical Storage of the Energy. Challenges in surface analysis**»
- Dr Emmanuel Nolot, Metrology Leader, CEA LETI, Grenoble, France, «**Metrology toolbox for advanced microelectronics**»



Surface Fest 2018

Already confirmed talks and speakers (2)

- Dr Hervé Montigaud, Saint Gobain Research. « **Glasses Surface characterisation of glazing by combination of techniques** ».
- Dr. Wolfram Hempel, Zentrum für Sonnenenergie- und Wasserstoff-Forschung Baden-Württemberg (ZSW) Photovoltaik: Materialforschung, Stuttgart, Germany, « **Improved GDOES Depth Profiling of CIGS Solar Cells by adding Nitrogen to Argon Sputter Gas** »
- Shiva Mohajernia, Anca Mazare, ImgonHwang, HelgaHildebrand, PatrikSchmuki, Department of Materials Science, WW4-LKO, University of Erlangen-Nuremberg, Erlangen, Germany, « **Depth elemental characterization of 1D self-aligned TiO₂ nanotubes using calibrated Radio Frequency Glow Discharge Optical Emission Spectroscopy (GDOES)** »
- Pr Tiberiu MINEA, Professeur, directeur du LPGP, Université Paris-Sud, Laboratoire de Physique des Gaz et des Plasmas, France, « **Surface and volume kinetics in plasmas. GD-OES case study.** »
- Andreea Vassiliu, Dr Gerard Hintz, COMET AG, Plasma Control Technology, Germany « **RF Technology - from component to system** »
- Pr Marisa Di Sabatino, Norwegian University of Science and Technology (NTNU), Department of Materials Science and Technology, Trondheim, Norway, « **Surfaces in silicon solar cells: deposition methods and advanced characterization** »
- P. Volovitch, A. Maltseva, ENSCP Chimie Paris Tech, Paris, France, « **On the application of GD-OES to analyze corrosion products** »
- L. Therese¹, J. Lo¹, Ph. Belenguer² and Ph. Guillot¹, ¹DPHE, INU Champollion, Université de Toulouse, Albi, France, ²Laplace, Université de Toulouse, CNRS, INPT, UPS, Toulouse, France « **Capacitively or/and Inductively Coupled Plasma sources in argon at low pressure for surface treatment. Modeling and experimental study.** »
- Lara Lobo, Rocio Muñoz, Beatriz Fernandez, Rosario Pereiro. University of Oviedo, Spain, « **Novel strategies for quantitative depth profile analysis of major and minor components by pulsed glow discharge time-of-flight mass spectrometry** »
- T. Galiullin, R. Pillai, D. Naumenko and W.J. Quadackers, High Temperature Corrosion and Corrosion Protection, Institute of Energy and Climate Research, Forschungszentrum Jülich GmbH, Germany : « **GDOES-assisted analysis of surface scale formation and oxidation-induced microstructural changes in high temperature Ni- and Co-base alloys** »
- Solène Béchu^{1,2}, Anaïs Loubat^{1,2}, Muriel Bouttemy², Jackie Vigneron², Anne-Marie Goncalves², Nathalie Simon², Arnaud Etcheberry², ¹Institut Photovoltaïque d'Ile-de-France (IPVF), 30 RD 128, 91120 Palaiseau, France, ² Institut Lavoisier de Versailles (ILV), UMR 8180 CNRS-UVSQ, 45 av. des Etats-Unis, Versailles, 78035, France, « **Sequential GD-OES/XPS Profiling Of III-V Based Solar Cells: Study of The GD-OES Crater Chemistry For XPS Analyses Reliability** »
- Dr Antoine Goullet, Institut des matériaux de Nantes, France, « **Application of ellipsometry to the study of thin oxide films and plasma processes control** »
- Dr Mickael Gilliot, Reims Champagne-Ardenne University, France, « **Inversion of ellipsometric spectra using constrained splines. Application to characterization of nanogranular ZnO with various morphologies.** »
- Dr Yann Battie, University of Metz, France, « **Ellipsometry of Au and Ag Colloidal Suspensions: New Experimental Setup to Characterize the Morphology of Metallic Nanostructures.** »